

# Lesson 8

## Case Studies

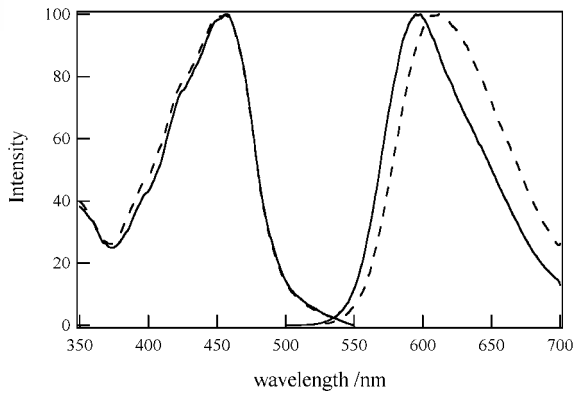
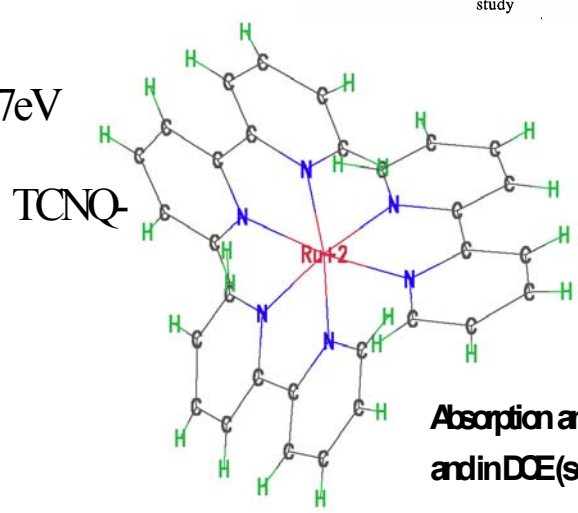
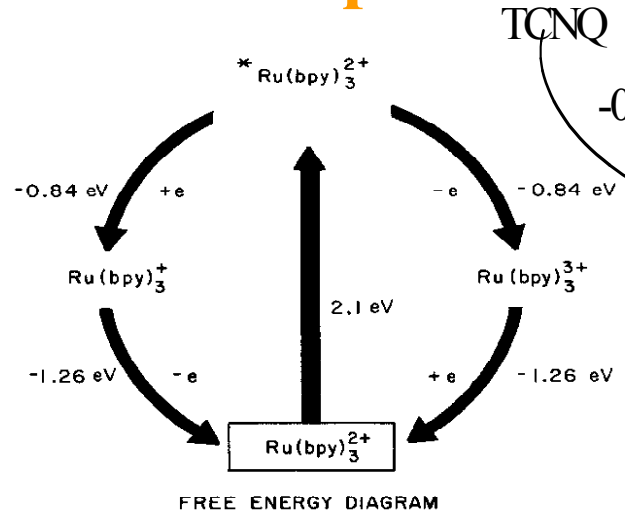
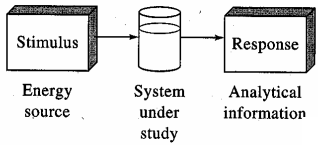
**You Will Learn Instrumentation for:**

- **A. Laser photochemistry and photoelectrochemistry**
- **B. Scanning Probe Microscopy**
- **C. PID control in chemical engineering**
  
- **As well as data treatment and presentation**

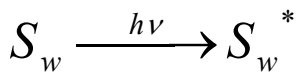
# A. Laser photochemistry and photoelectrochemistry

## (1) Laser photochemistry

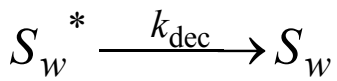
### a. Principle



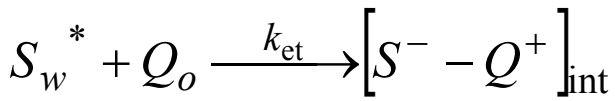
Absorption and fluorescence spectra of  $Ru(bpy)_3^{2+}$  in water (dashed line) and in DOE (solid line)



Photoexcitation (1)



Decay of the excited state (2)



Electron transfer (ET) (3)

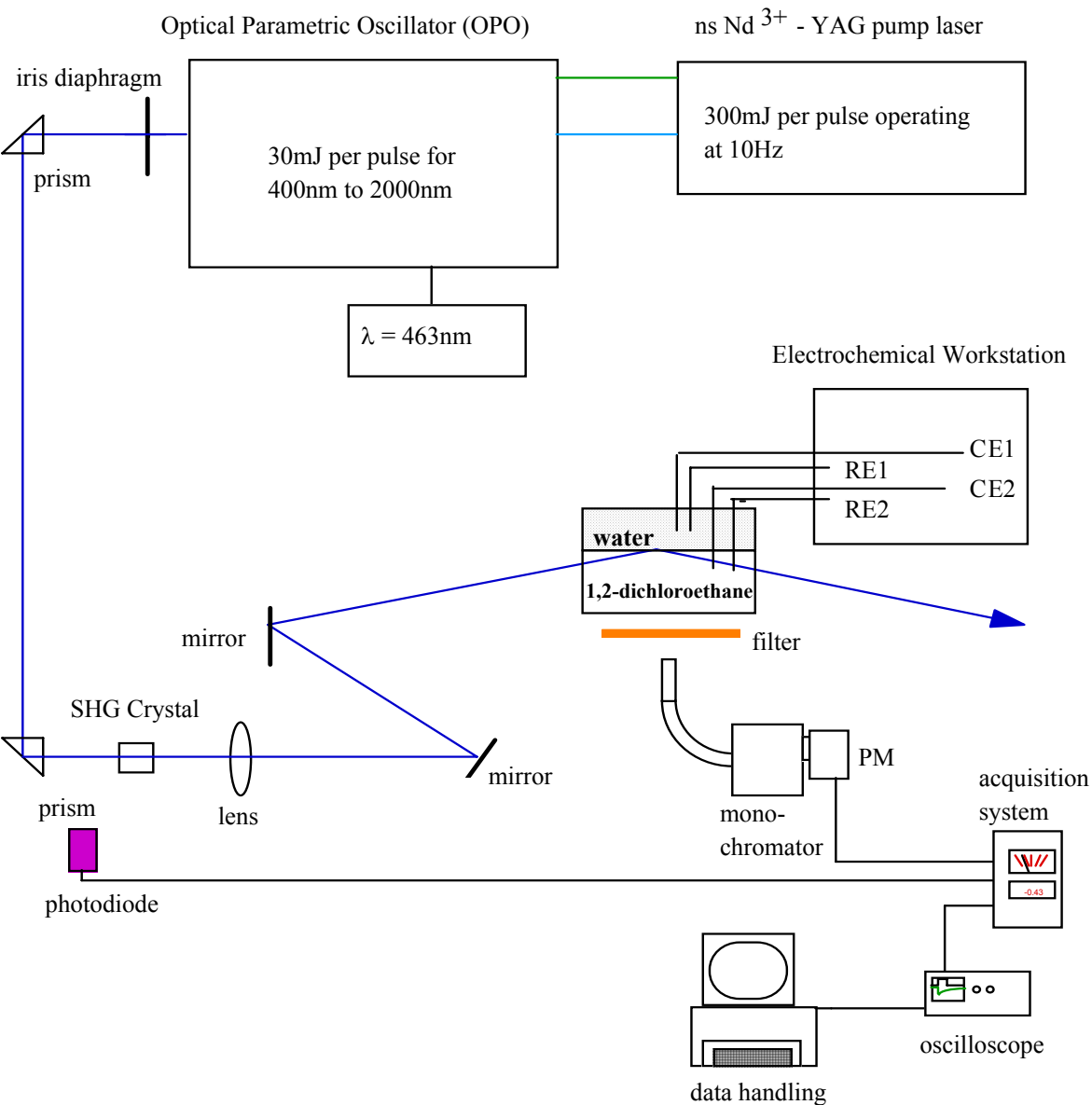
$$\frac{1}{\tau_{app}} = \frac{1}{\tau_0} + k_q c_q$$

Stern-Volmer Equation to measure ET rate

# (1) Laser photochemistry

## b. Instrumentation

Z. F. Ding, R. G. Wellington, P. F. Brevet, H. H. Girault, "Spectroelectrochemical Studies of Ru(bpy)<sub>3</sub>(2+) at the Water/1,2-Dichloroethane Interface", *J. Phys. Chem.* 100 (1996) 10658-10663.

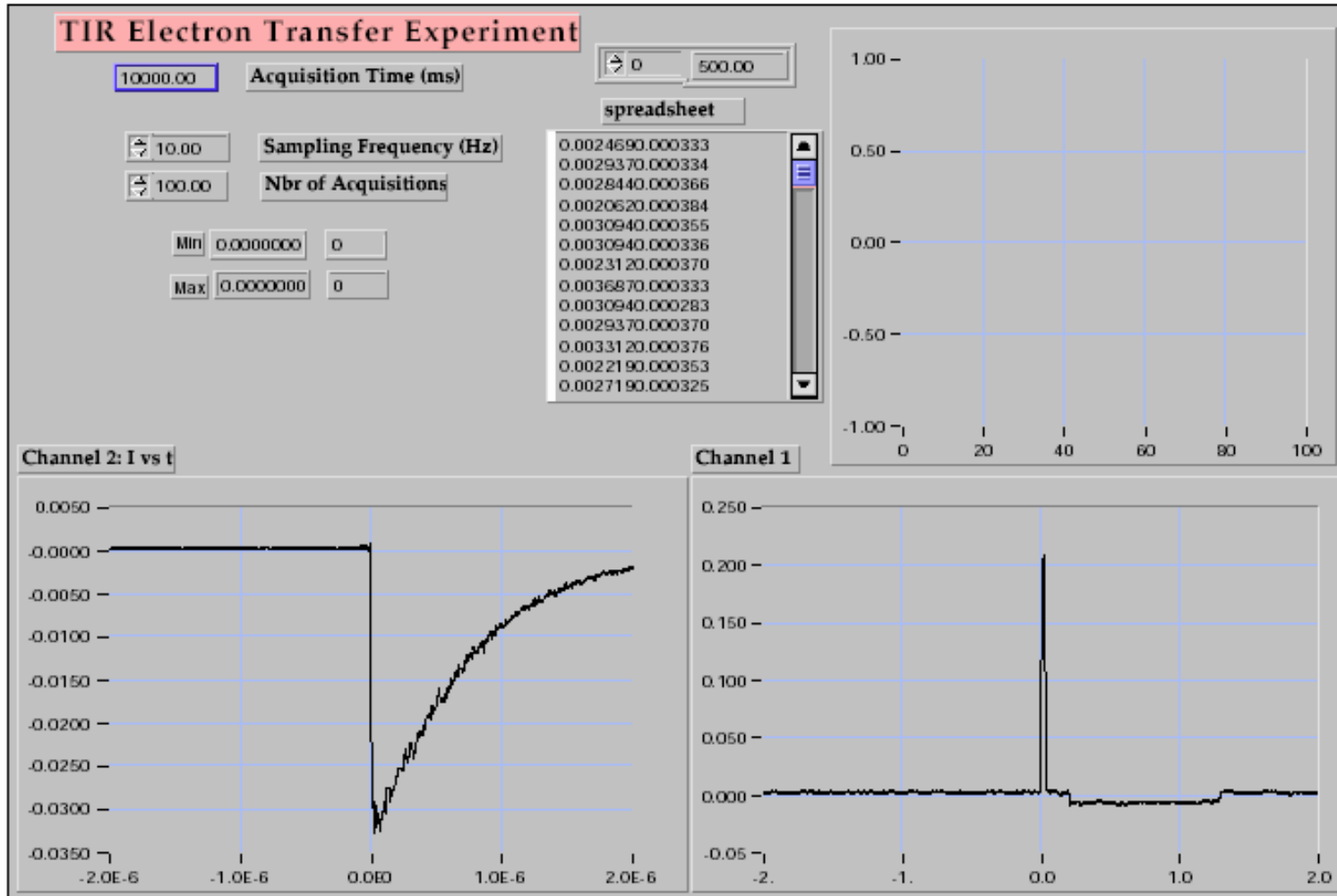


# (1) Laser photochemistry

## b. LabVIEW Data Acquisition

GPIB Oscilloscope driver

Front Panel

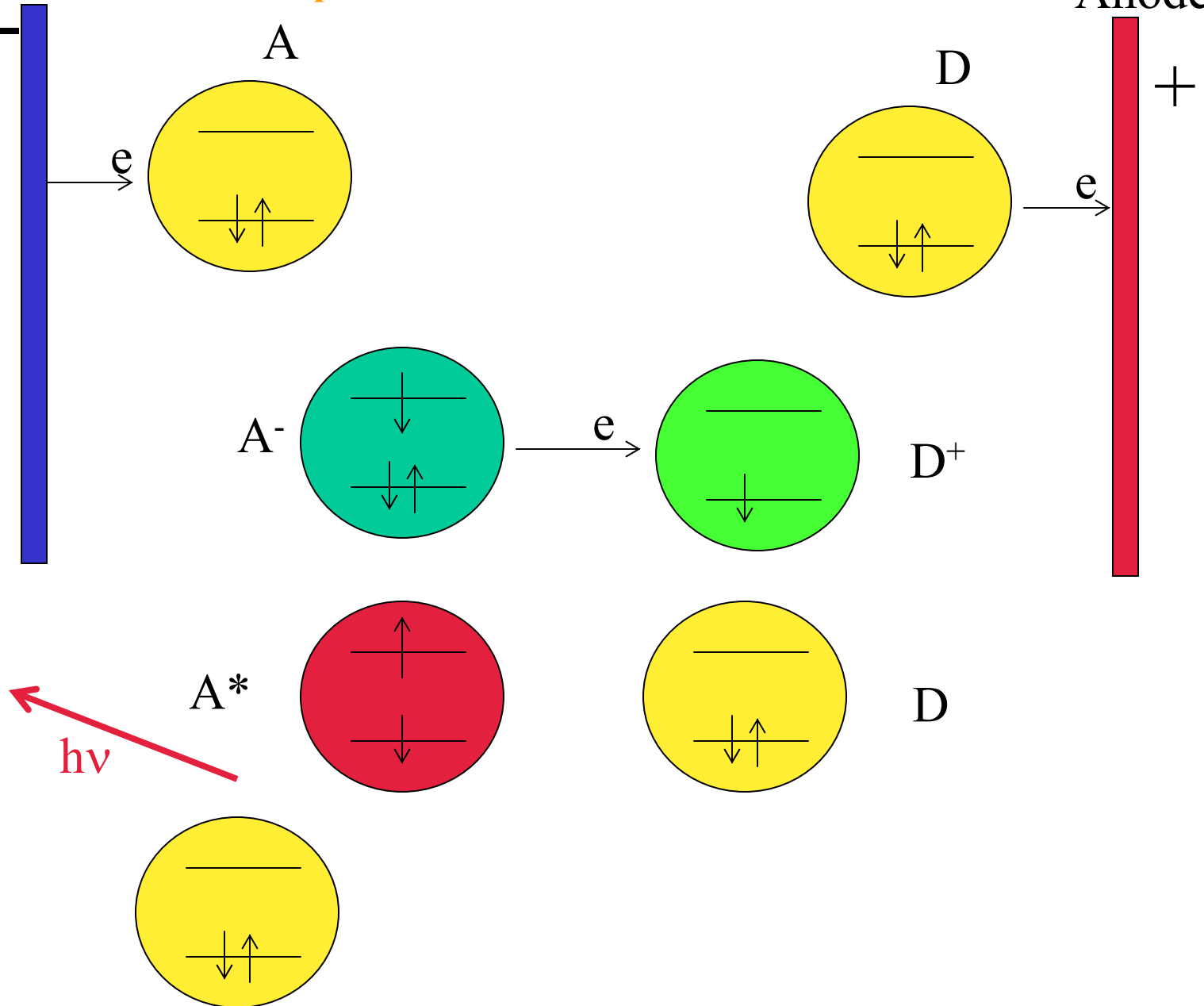


## (2) photochemistry-Electrogenerated Chemiluminescence

### a. Principle

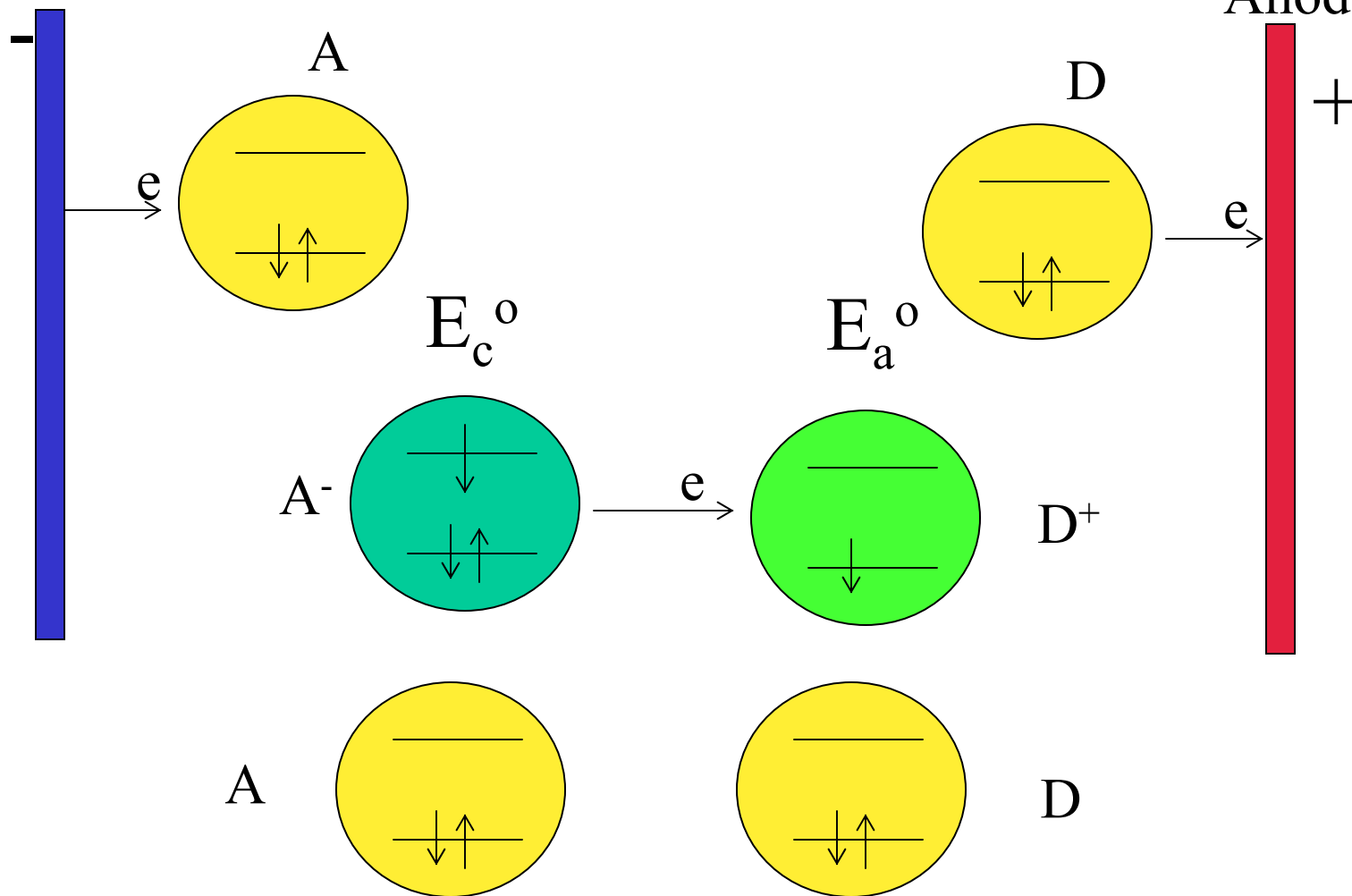
Cathode

Anode



Cathode

Anode

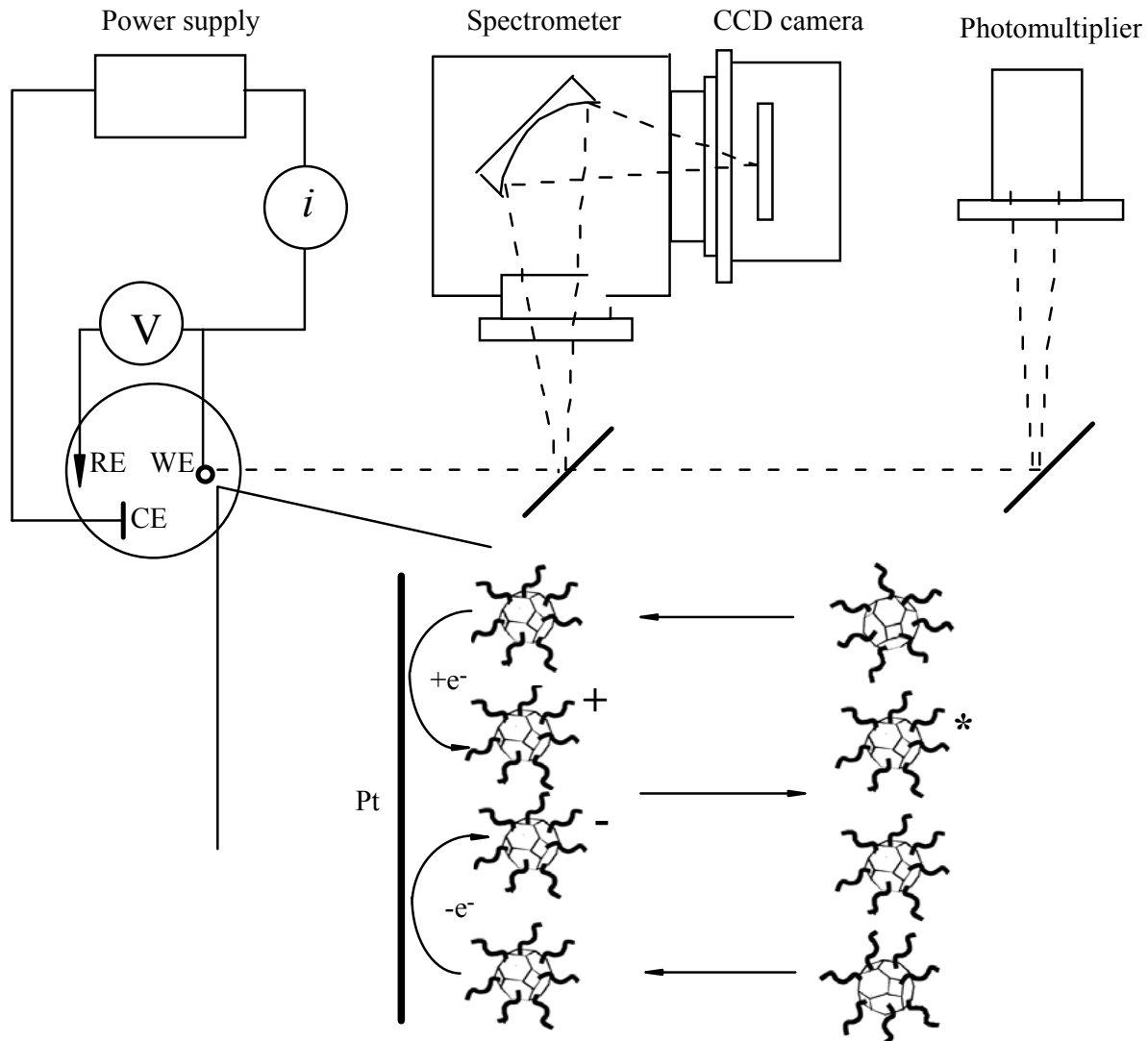


Criterion for excited state formation

$$E_a^0 - E_c^0 - 0.1 > E_S$$

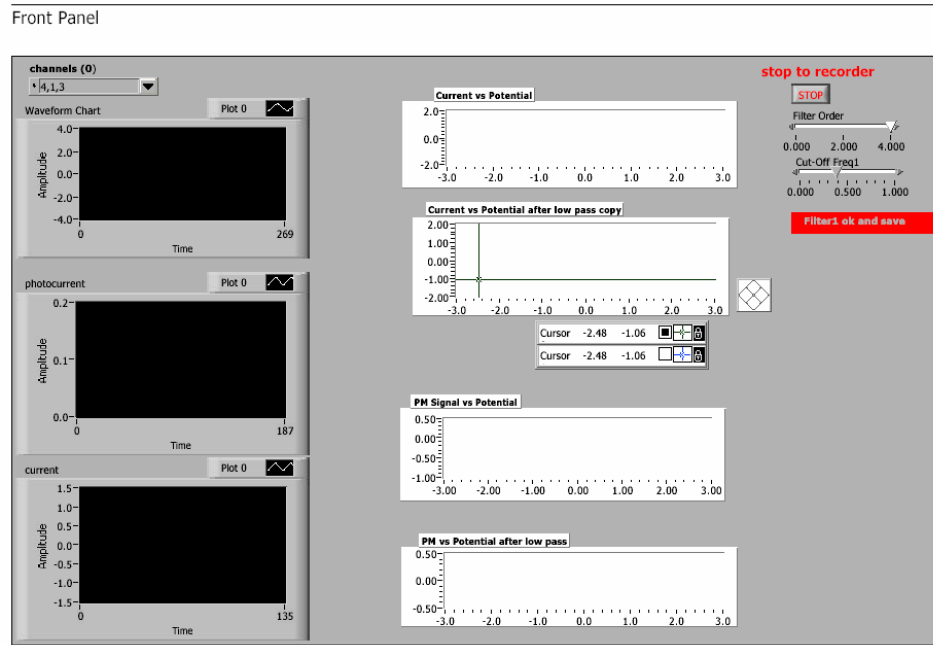
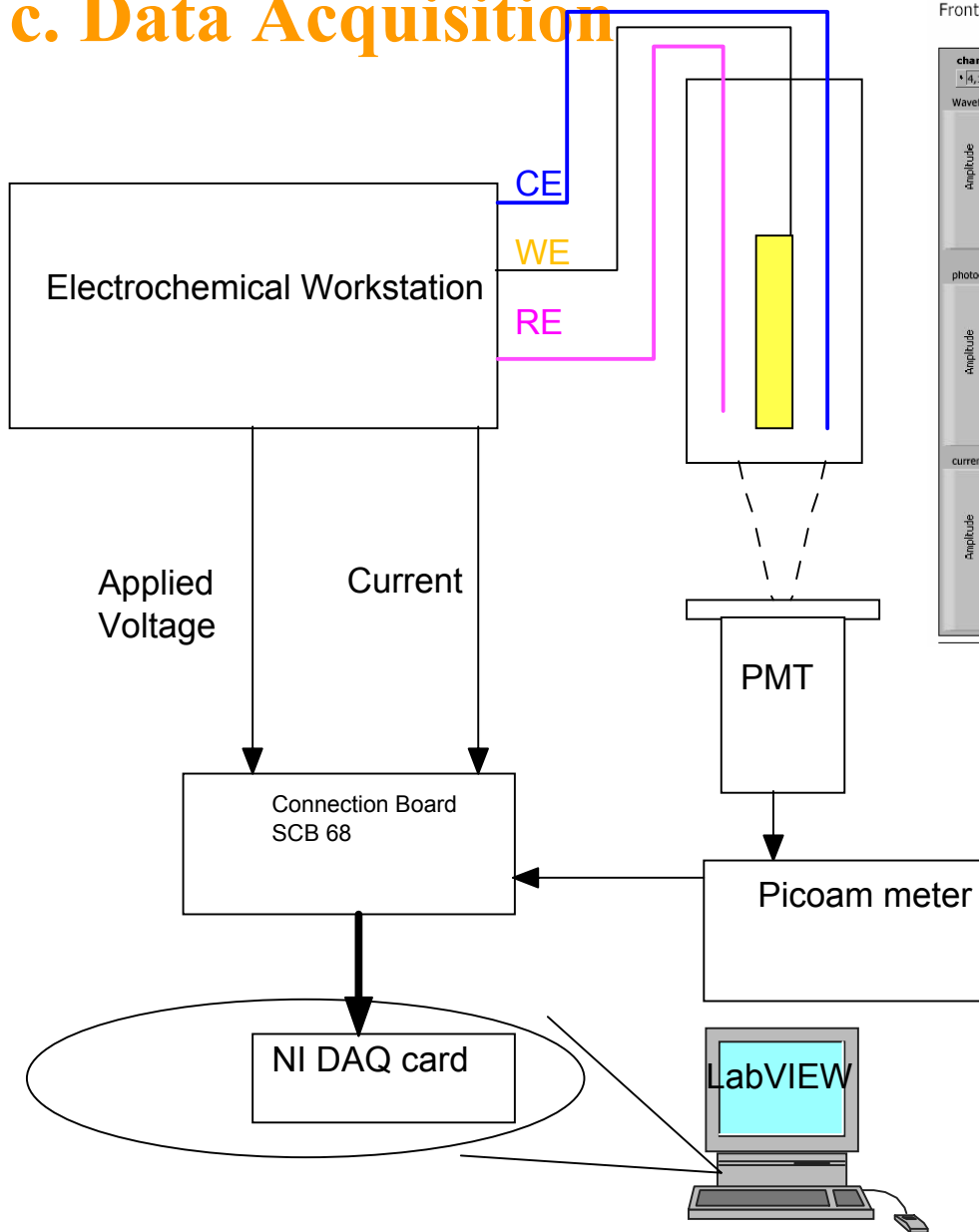
# (2) photochemistry-Electrogenerated Chemiluminescence

## b. Instrumentation



# (2) photochemistry-Electrogenerated Chemiluminescence

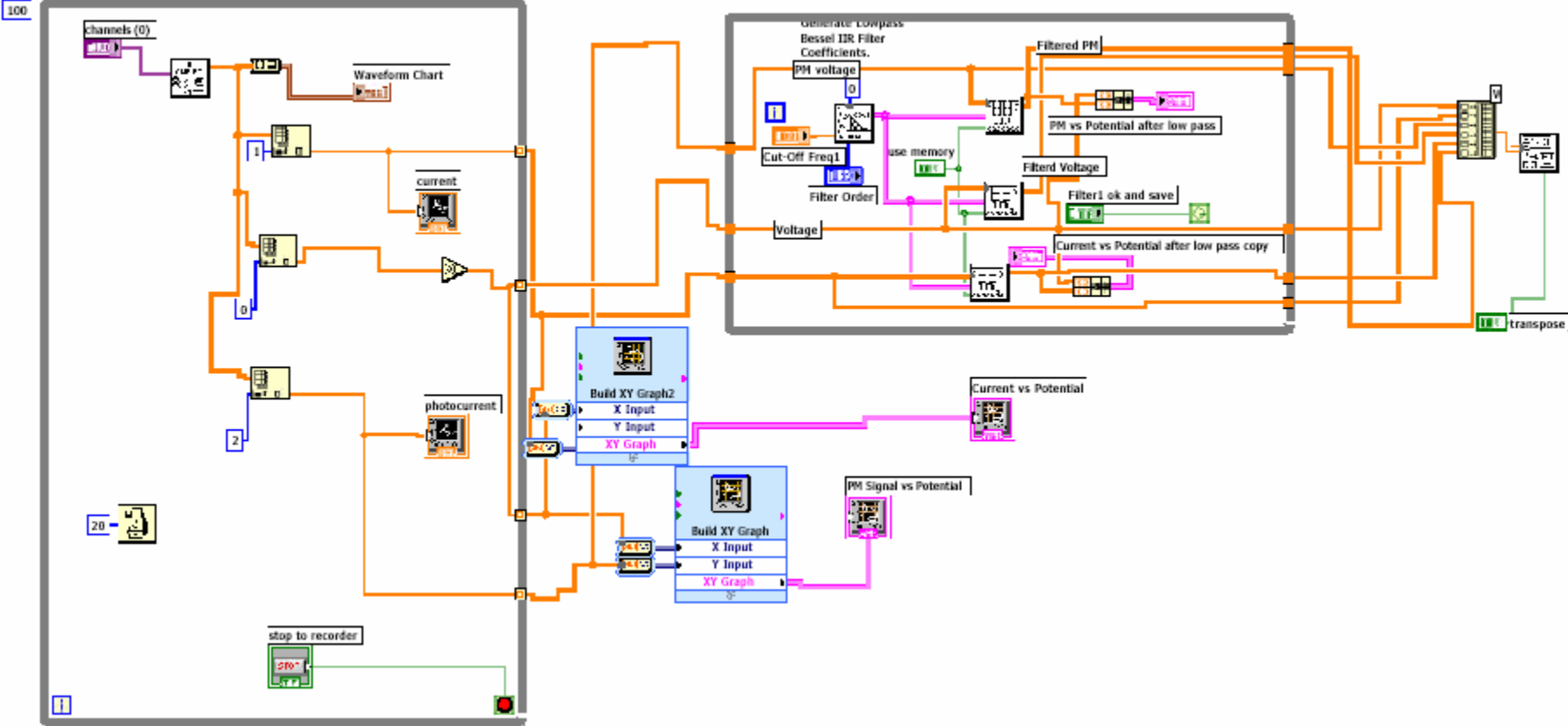
## c. Data Acquisition





# ECL\_PMT610A.vi

## Block Diagram

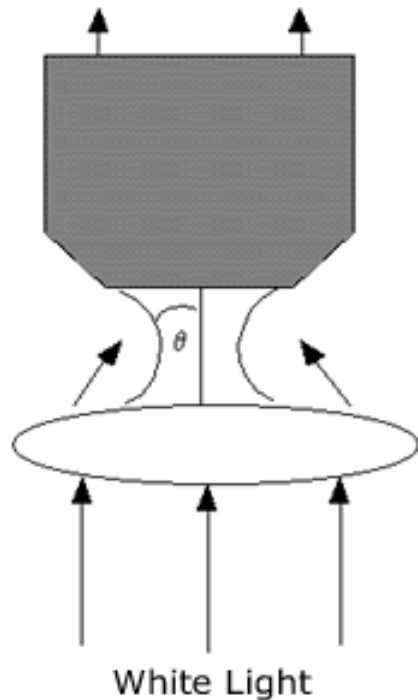


# B. Scanning Probe Microscopy

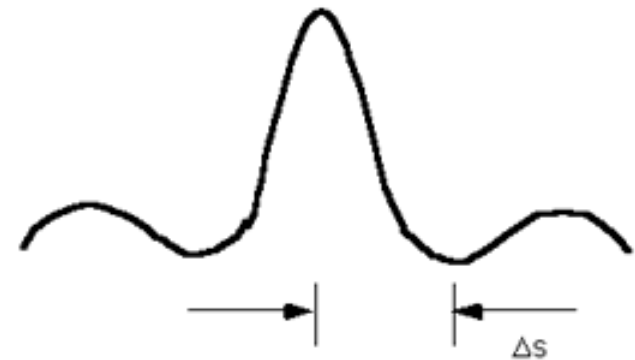
## Near-field Scanning Optical Microscopy (NSOM or SNOM)

### a. principle

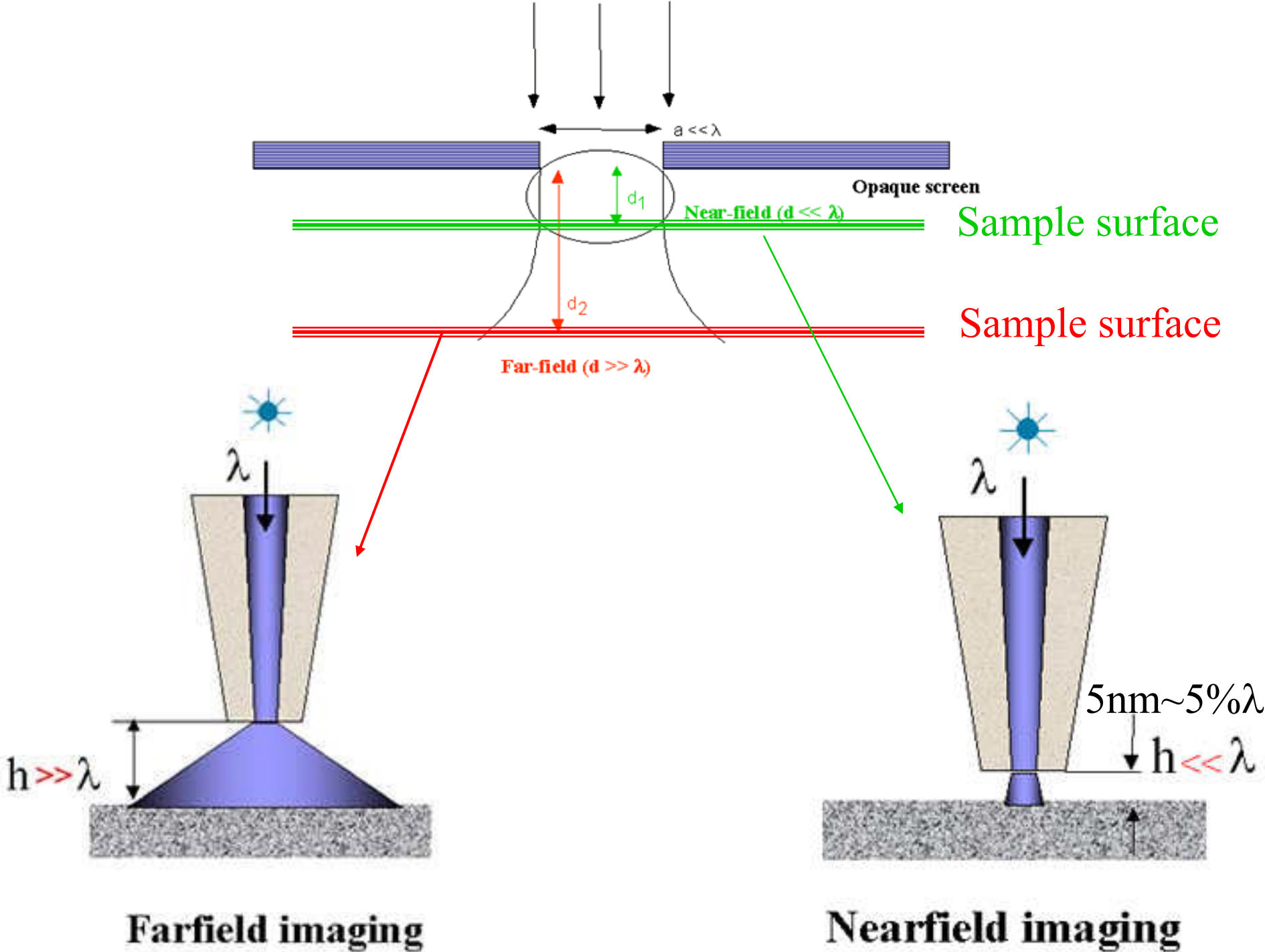
The diffraction limit in conventional microscopy  
(Abbe diffraction limit)



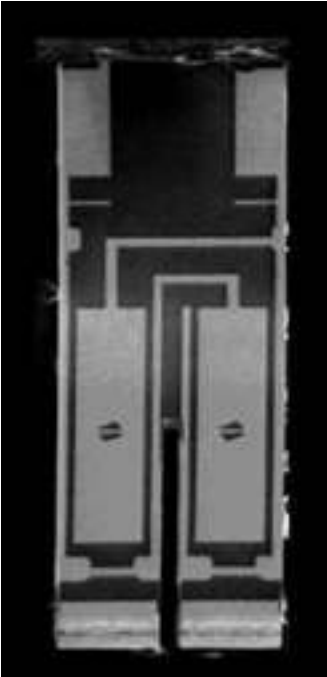
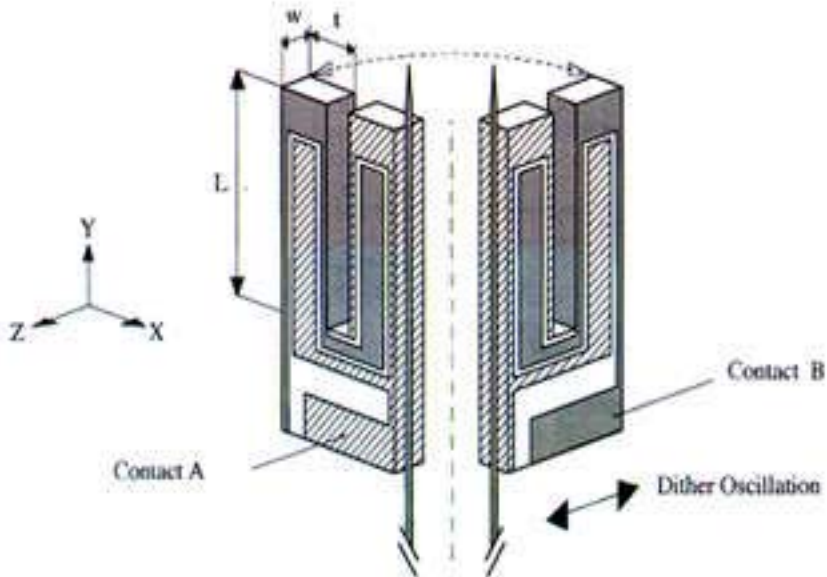
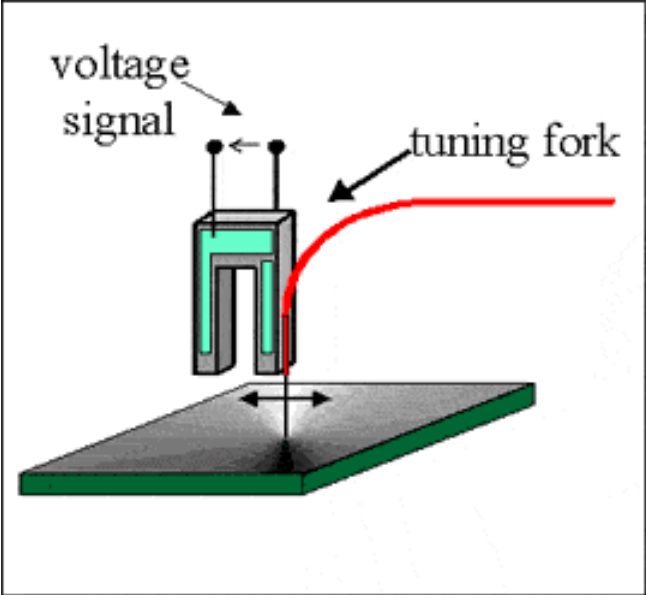
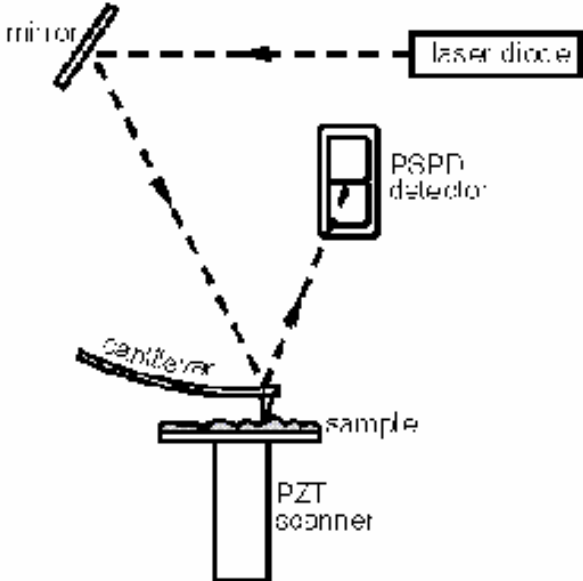
Beam cross-section at focus



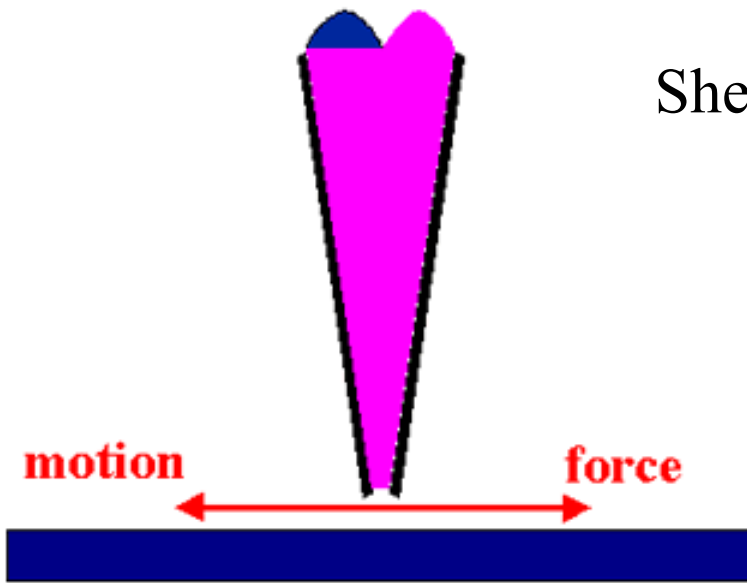
$$\Delta S = \frac{0.61\lambda}{NA(\text{numerical aperture})}$$
$$= \frac{0.61\lambda}{n \sin \theta} \approx \lambda/2$$



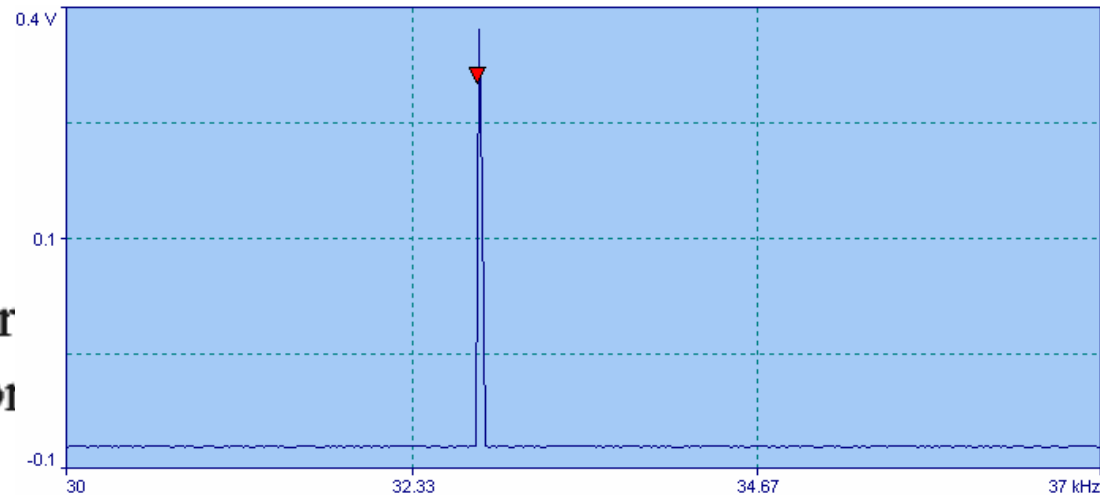
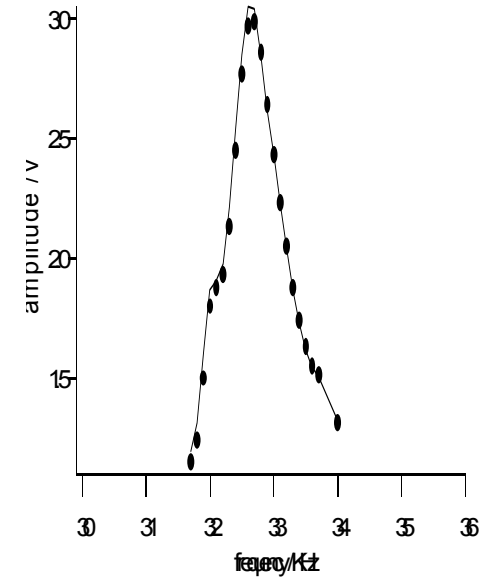
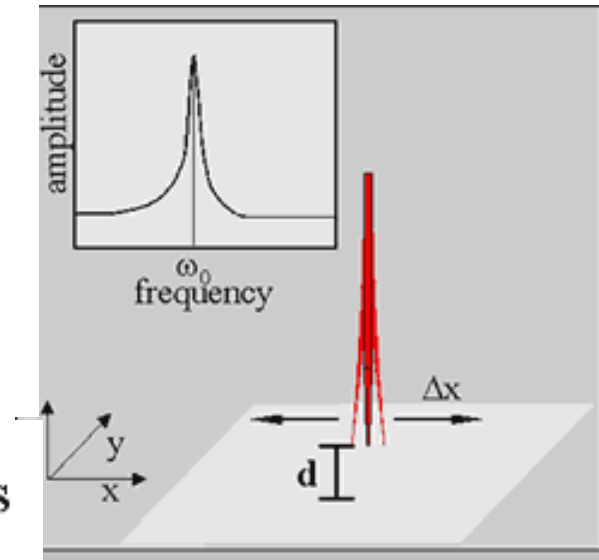
# Positioning the probe



# Shear force detection

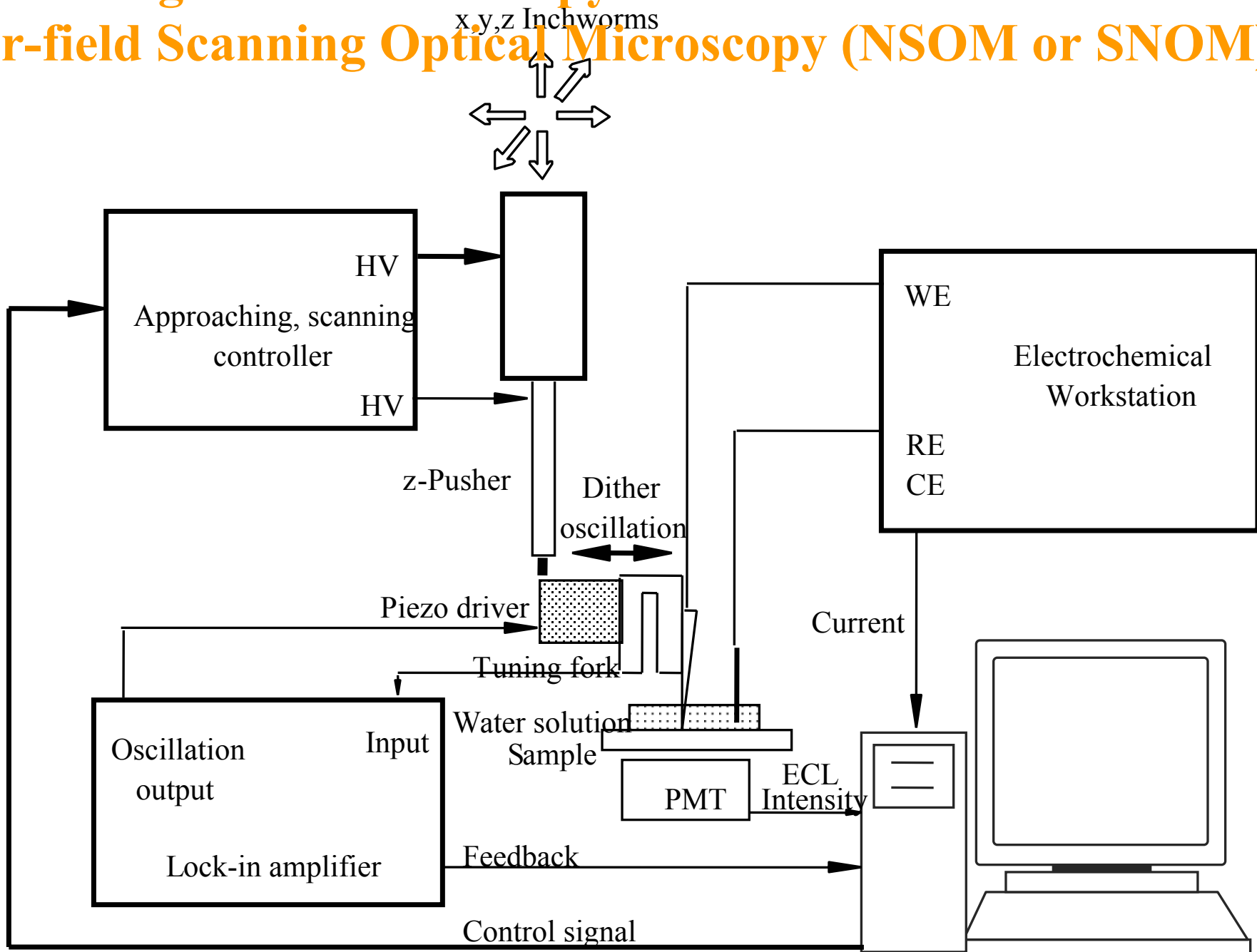


- Lateral vibration of tip at its resonance frequency  $\omega_0$
- Measurement of oscillation amplitude  $\Delta x$  or phase  $\varphi$
- Oscillation amplitude and phase are changed by shear forces and are a measure for the tip-sample distance  $d$



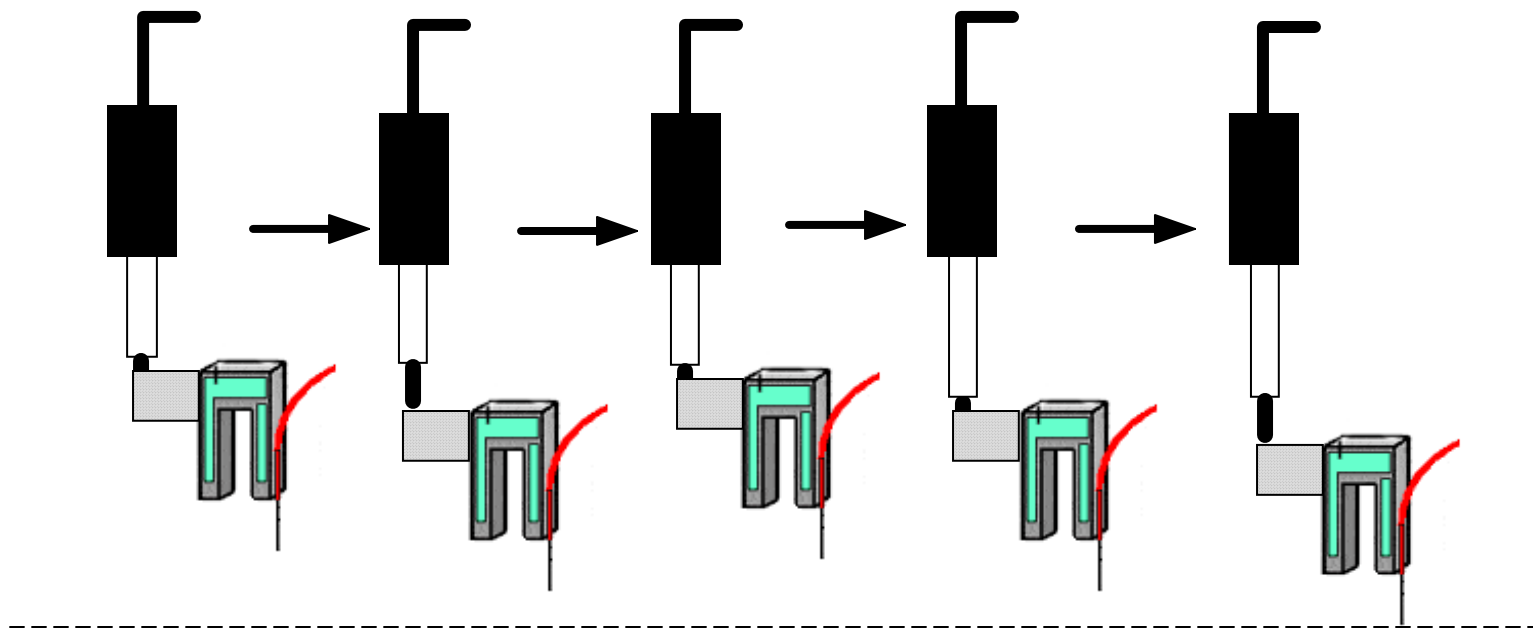
# B. Scanning Probe Microscopy

## Near-field Scanning Optical Microscopy (NSOM or SNOM)



# positioning of the tip to the substrate

P-F-6.4 $\mu\text{m}$  P-W-6.4 $\mu\text{m}$  I-F-6.4 $\mu\text{m}$  P-F-6.4 $\mu\text{m}$



Y. Zu, Z. Ding, J. Zhou, Y. Lee, A. J. Bard, "Scanning Optical Microscopy with an Electrogenerated Chemiluminescent Light Source at a Nanometer Tip", *Anal. Chem.* 73 (2001) 2153-2156

# B. Scanning Probe Microscopy

## Near-field Scanning Optical Microscopy (NSOM or SNOM)

### b. Instrumentation

Shear-force device: tuning fork driven by a lock-in amplifier

Feedback: lock-in amplifier

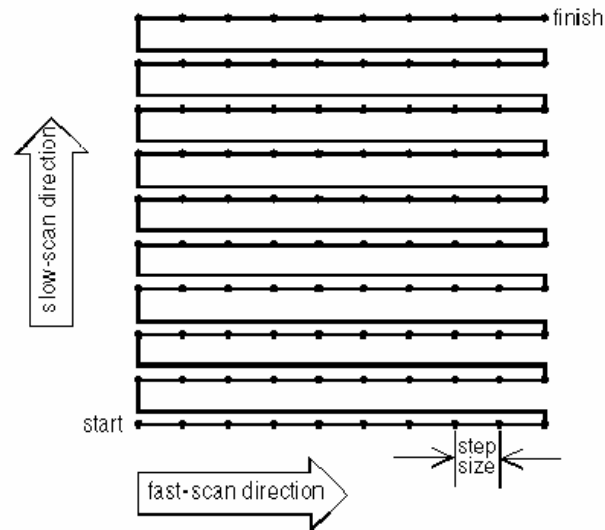
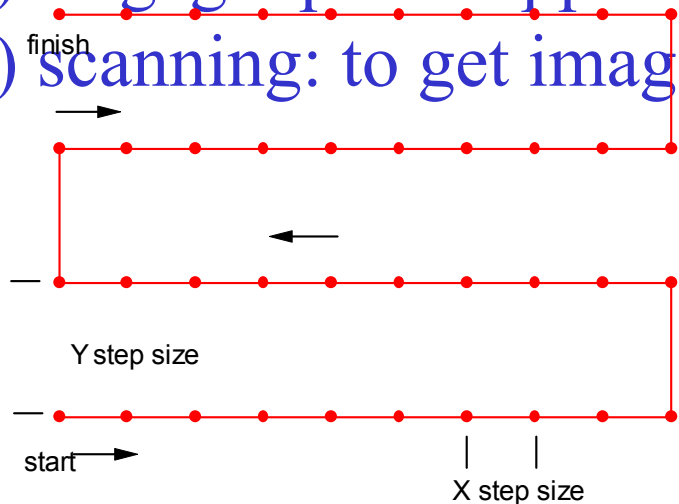
micro-positioner: 1. inchworm motor stage+controller

2. Piezo pusher+controller(using DAQ out)

Two processes

(1) Engage: probe approaches

(2) scanning: to get images



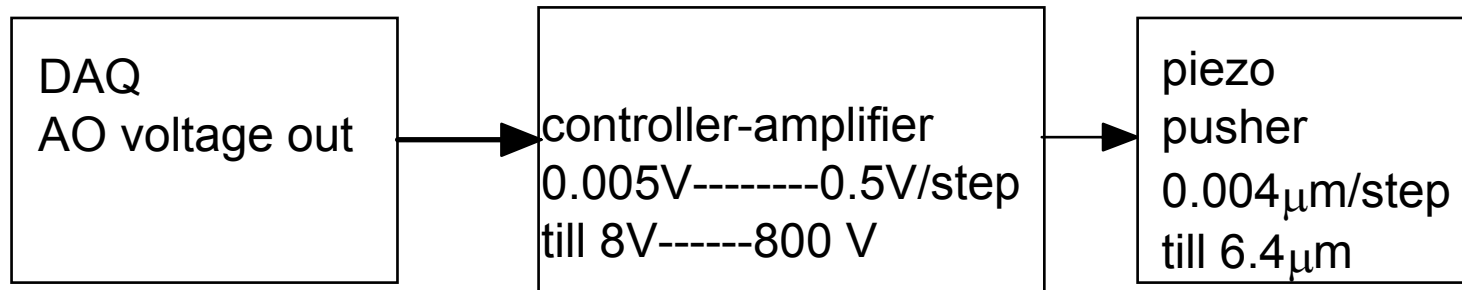
near-field



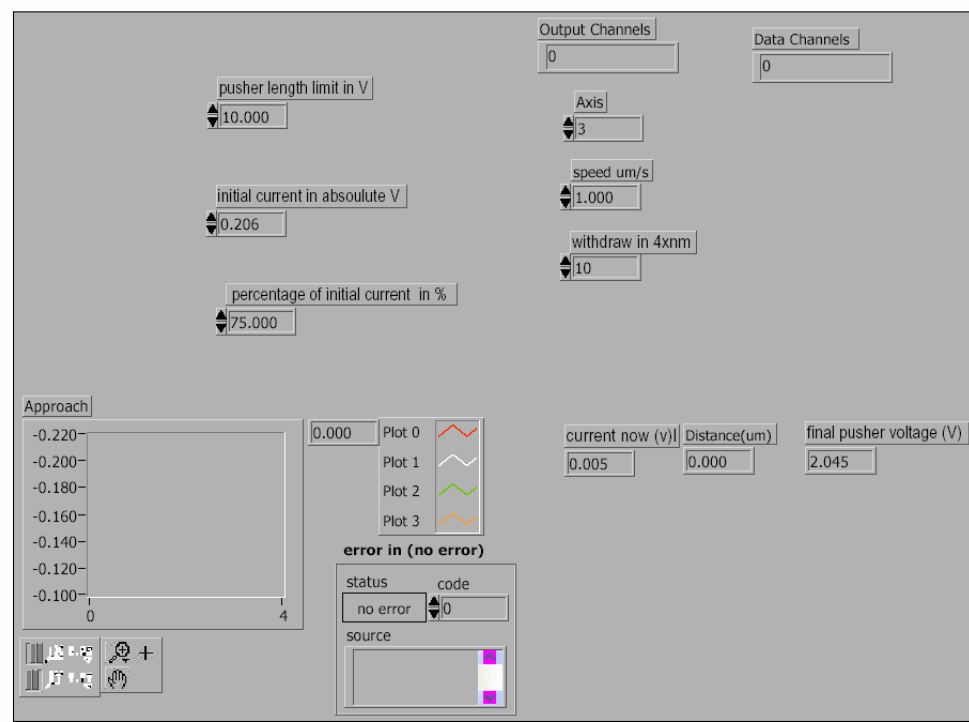
# B. Scanning Probe Microscopy

## Near-field Scanning Optical Microscopy (NSOM or SNOM)

### b. Programming in LabVIEW



Front Panel

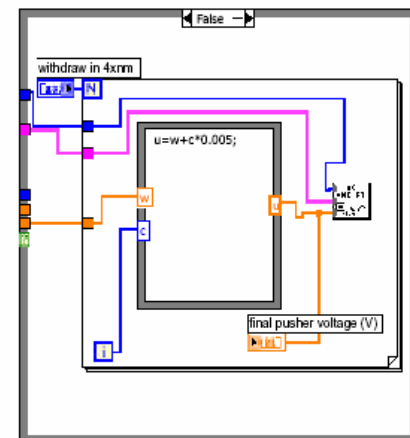
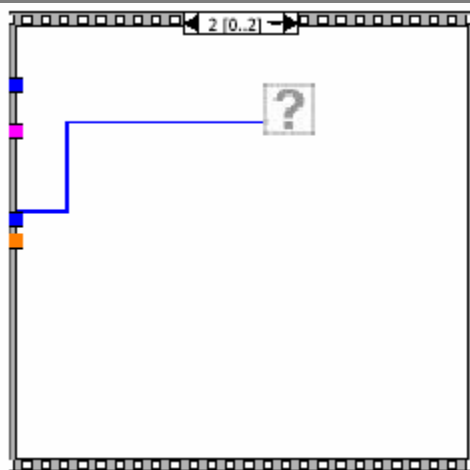
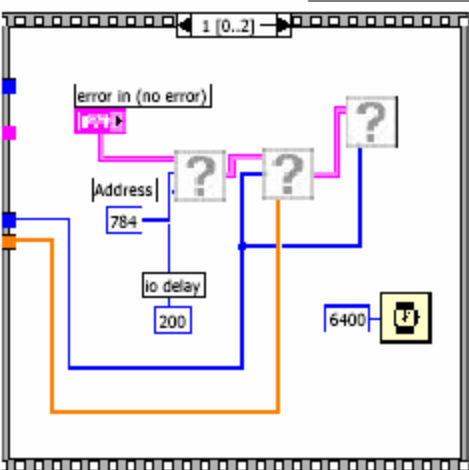
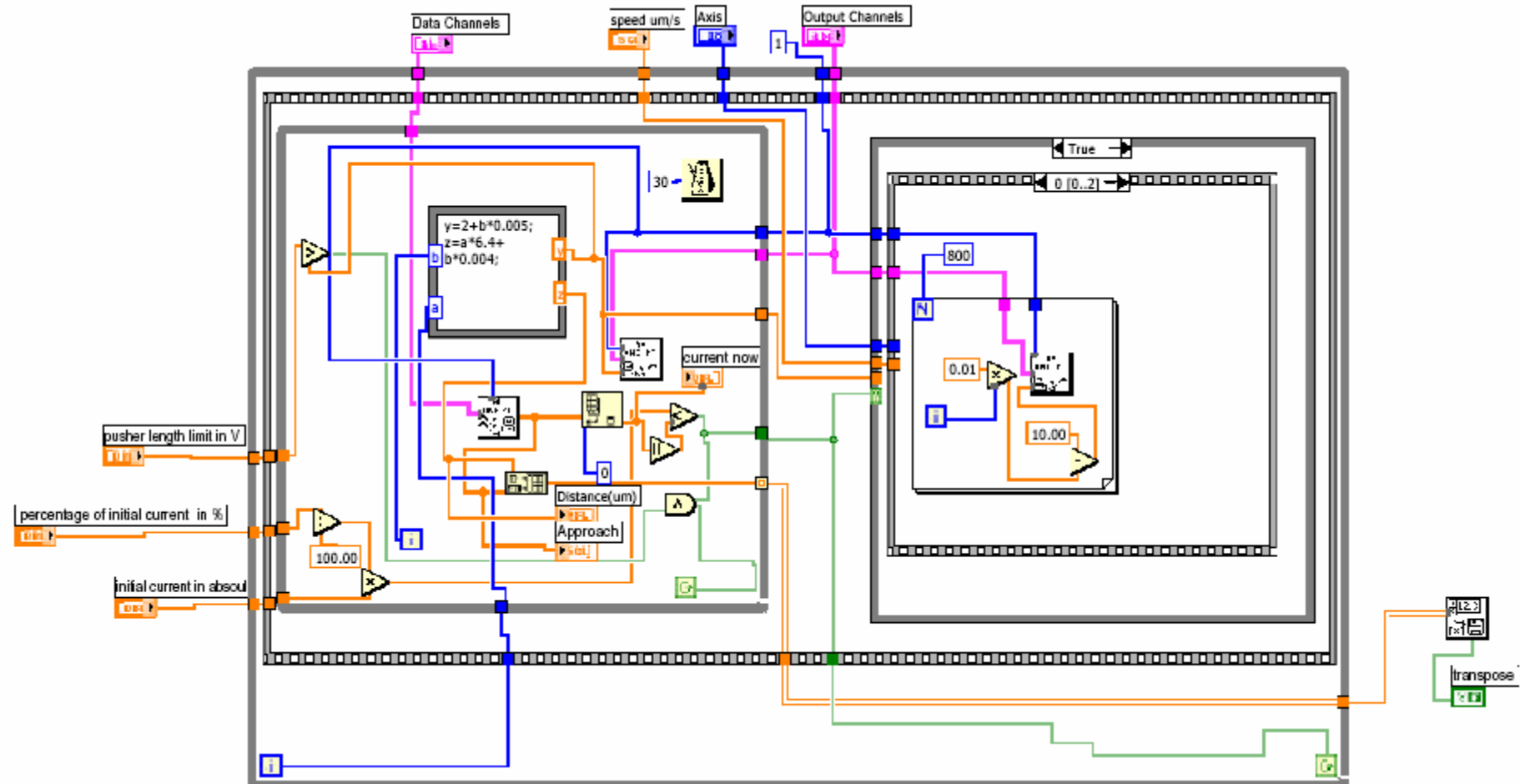


Inchworm controller  
at speed of 1  $\mu\text{m/s}$

time counter  
on the DAQ  
6400 ms

Inchworm  
move 6.4  $\mu\text{m}$

Finally withdraw 40 nm





## C. PID control in chemical engineering

In the PID (Proportional-Integral-Derivative) controller, the setpoint is compared to the process variable to obtain the error

$$e = SP - PV.$$

You can then calculate the controller action theoretically as

$$u(t) = K_c \left( e + \frac{1}{T_i} \int_0^t e dt + T_d \frac{de}{dt} \right),$$

where  $K_c$  is controller gain. If the error and the controller output have the same range, that is  $-100\%$  to  $100\%$ , controller gain is the reciprocal of *proportional band*.  $T_i$  is the integral time in minutes (also called *reset time*), and  $T_d$  is the derivative time in minutes (also called *rate*). The proportional action is

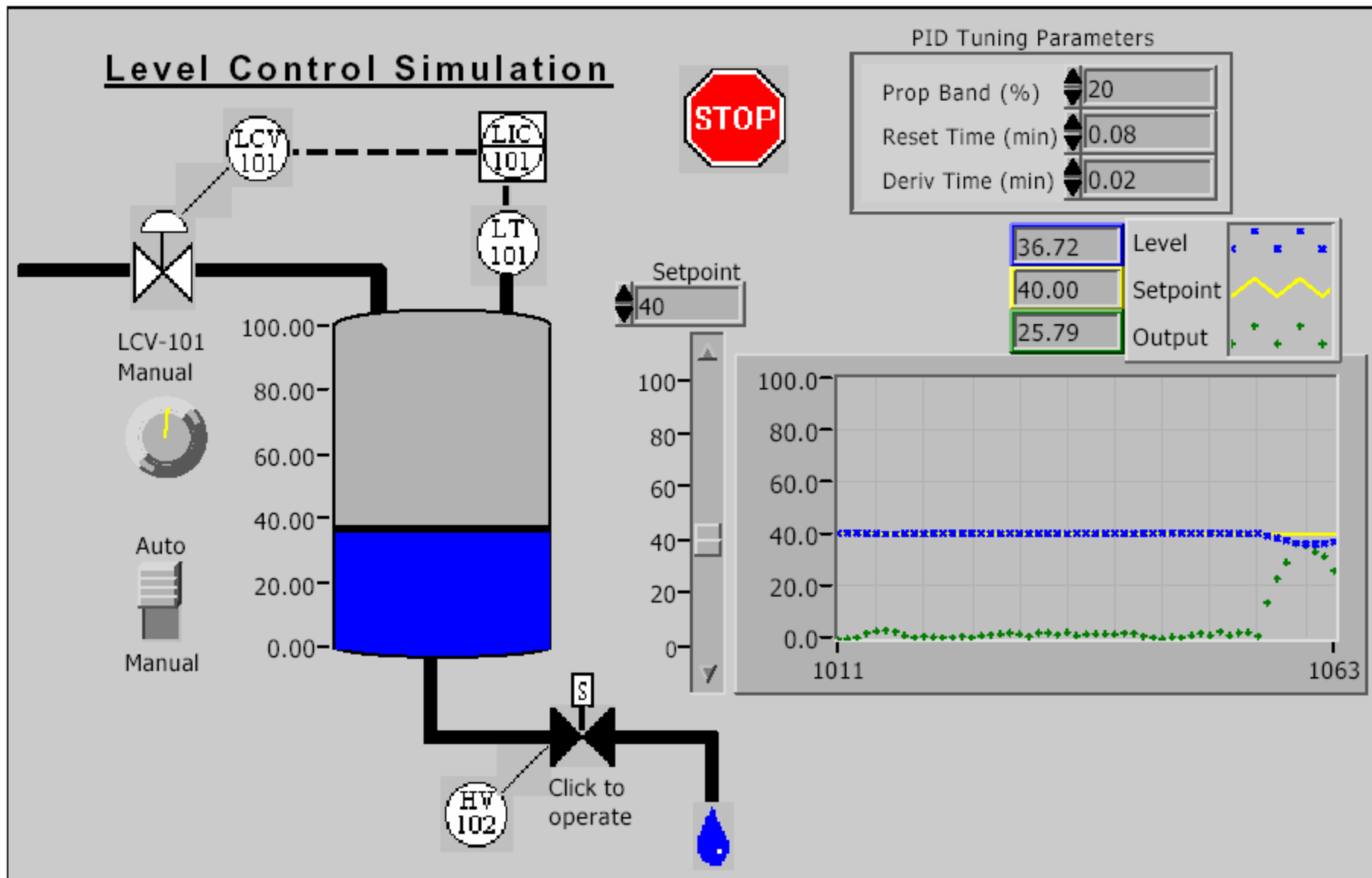
$$u_p(t) = K_c e,$$

the integral action is

$$u_I(t) = \frac{K_c}{T_i} \int_0^t e dt,$$

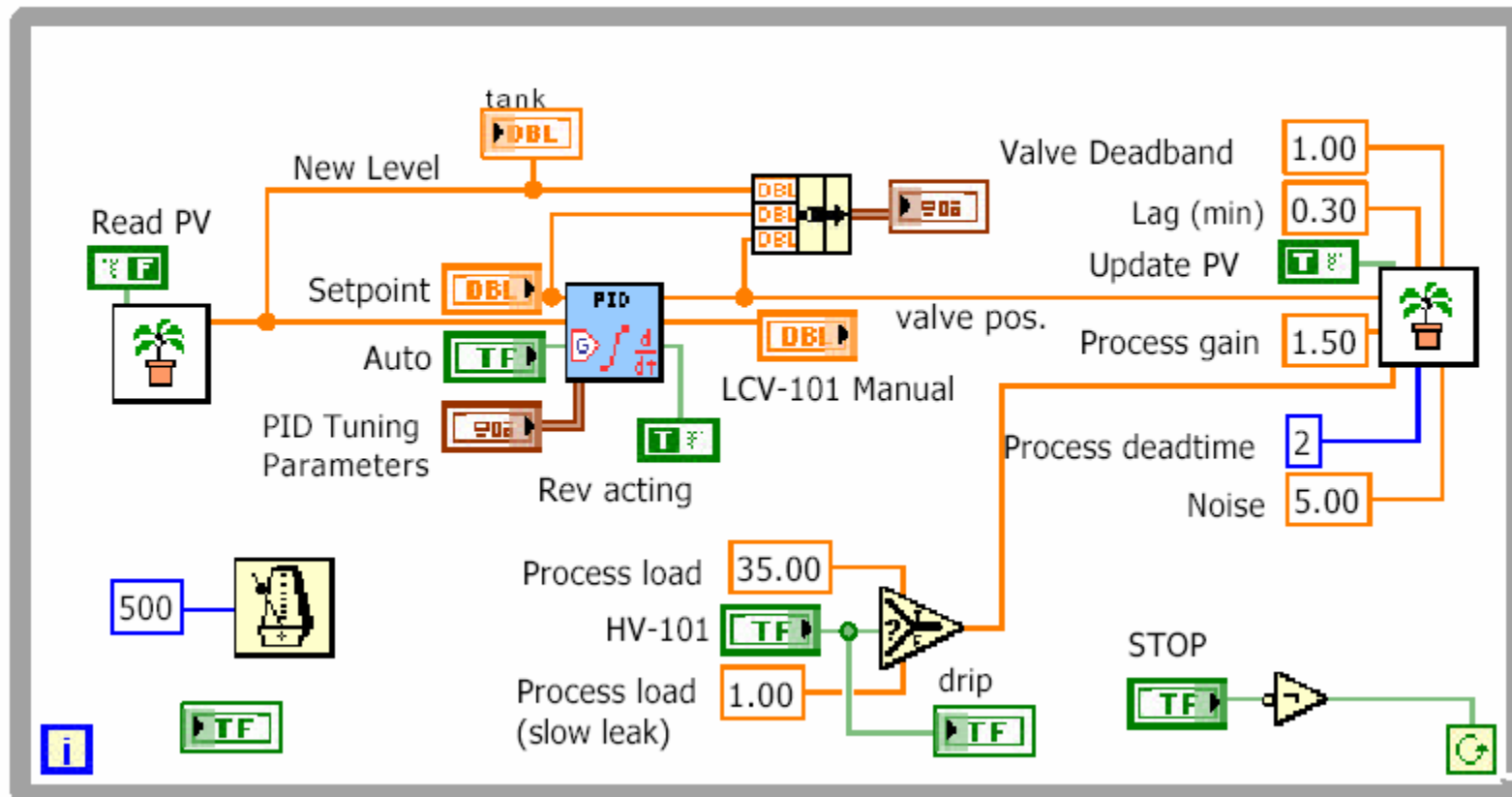
and the derivative action is

$$u_D(t) = K_c T_d \frac{de}{dt}.$$



The Plant Simulator subVI, which simulates this process, reads and delays the previous valve position and scales it according to the process gain. The gain represents how fast the tank fills versus the position of the valve. The process load value depends on the state of HV-101, the drain valve. When you open the valve, the tank level drops.

Block Diagram



# PID application to Scanning Probe Microscopy

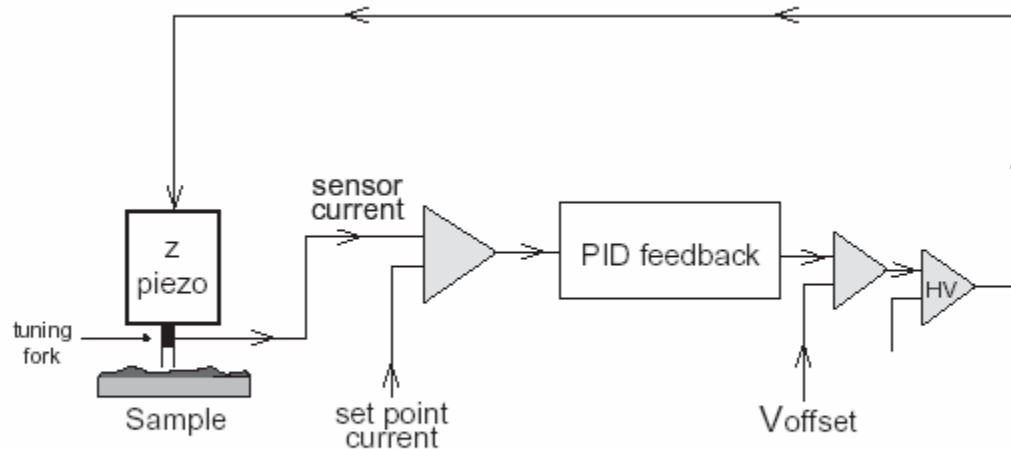


Figure 4-1. Feedback loop.

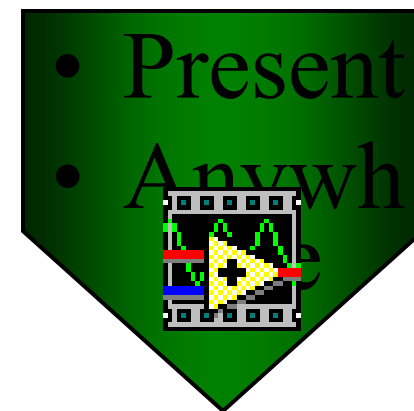
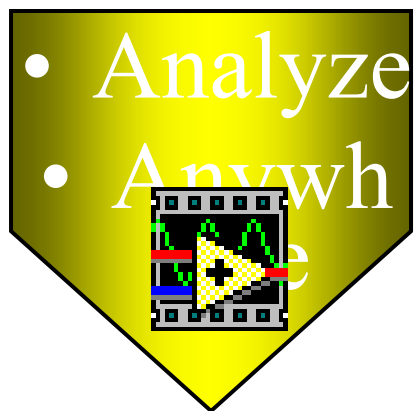
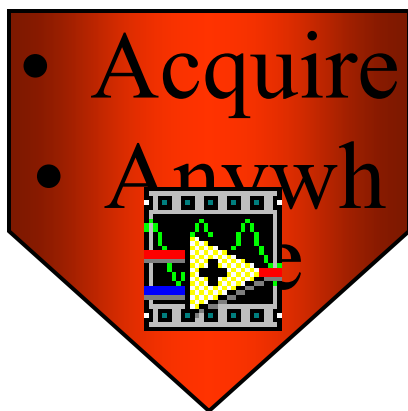
- Proportional gain responds quickly to small features but is not optimized to respond to large features.
- Integral gain controls the response time of the piezo to large, slow sensor changes. If set too high, integral gain can result in oscillation or noise in the image. This oscillation will be apparent on the oscilloscope signals.
- Derivative gain tends to reduce oscillation but may amplify high-frequency noise.

## References

1. Z. F. Ding, R. G. Wellington, P. F. Brevet, H. H. Girault, "Spectroelectrochemical Studies of Ru(bpy)<sub>3</sub>(<sup>2+</sup>) at the Water/1,2-Dichloroethane Interface", *J. Phys. Chem.* 100 (1996) 10658-10663.
2. Z. Ding, B. M. Quinn, S. K. Haram, L. E. Pell, B. A. Korgel, A. J. Bard, "Electrochemistry and electrogenerated chemiluminescence from silicon nanocrystal quantum dots", *Science* 296 (2002) 1293-1297.
3. Y. Zu, Z. Ding, J. Zhou, Y. Lee, A. J. Bard, "Scanning Optical Microscopy with an Electrogenerated Chemiluminescent Light Source at a Nanometer Tip", *Anal. Chem.* 73 (2001) 2153-2156.



# Summary



In-situ reaction monitoring, electrochemistry, spectroelectrochemistry can easily be done.